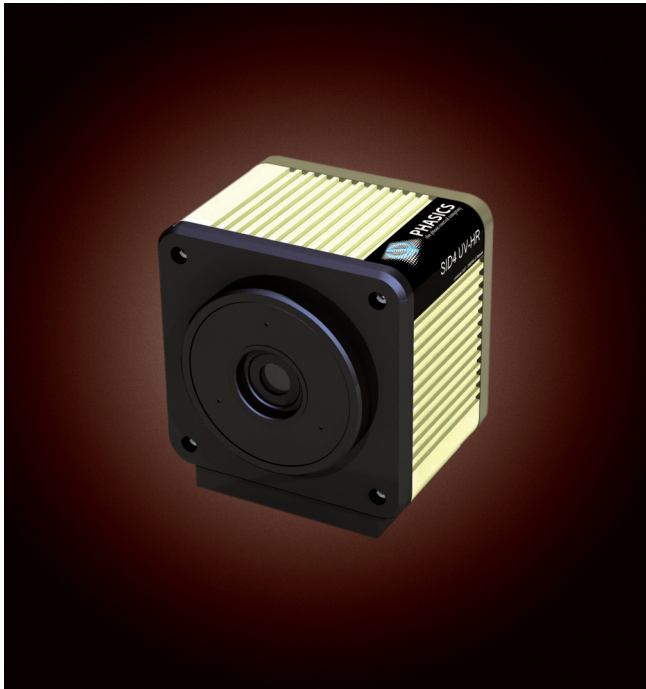


# SID4 UV-HR

## WAVE FRONT SENSOR



→ PHASICS extends the SID4 product line to UV wavelengths. With the **SID4 UV-HR**, all the advantages of the PHASICS technology (4-wave lateral shearing Interferometry\*) are accessible from 190 nm to 400 nm.

The sampling resolution of 250 x 250 measurement points is adapted for **optical components characterization** (used in lithography, semiconductor...) and also in **surface inspection** (wafers inspection for instance).

With such sensitivity, SID4 UV-HR is the cost effective UV solution for high resolution characterization.

### ↓ SPECIFICATIONS

Aperture dimension	8.0 x 8.0 mm <sup>2</sup>
Spatial resolution	32 μm
Sampling	250 x 250
Wavelength range	190 - 400 nm
Accuracy (absolute)	10 nm
Sensitivity	0.5 nm
Dynamic	> 200 μm
Radius of curvature	10 mm to +∞
Sensitivity curvature measurement	< 5. 10 <sup>-4</sup> m <sup>-1</sup>
Analysis rate	1 fps
Acquisition rate	30 fps
Dimensions (l x H x L)	95 x 105 x 84 mm
Weight	900 g

### ↘ KEY FEATURES

- Very high resolution (250 x 250)
- Large analysis pupil (8,0 mm x 8,0 mm)
- UV spectrum covered
- High sensitivity (0,5 nm)
- Optimal signal to noise ratio
- Adapted to optics characterization